

## New generation of FISCHERSCOPE® X-RAY: XDLM and XDAL series



The newest generation of the proven FISCHERSCOPE® XDAL and XDLM x-ray spectrometers is now available. The development process focused on the unit's performance, ergonomics and design.

The XDLM spectrometers with micro focus tube and proportional counter tube are ideally suited for the inspection of parts where small structures are measured. Typical applications are measurements on pc-boards, plug contacts and electronic components. XDLM spectrometers are equipped with four exchangeable apertures and a programmable XY(Z) measuring stage. This makes them ideally suited for testing mass-produced parts.

The XDAL spectrometers with silicon PIN detectors provide reliable analysis results and coating thickness readings even with a small concentration and very thin coatings. With their fast and highly precise XY(Z) measuring stage, they are ideally suited for automated sample measurements.

The XDAL and XDLM spectrometers have an excellent long-term stability, which is reflected in a significantly reduced calibration effort, among other things. Using the FISCHER fundamental parameter method, coating systems as well as solid and liquid samples can be analyzed standard-free.

Fischer Technology is U.S. manufacturer of coating thickness measurement, material analysis, micro-hardness measurement and materials testing.

Fischer Technology, Inc.

[www.fischer-technology.com](http://www.fischer-technology.com)

[info@fischer-technology.com](mailto:info@fischer-technology.com)

(800)243-8417 or (860)683-0781